



Object Detection Technology

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Message from the Guest Editors

Object detection refers to the identification and tracking of important targets in several types of data and electromagnetic signals, such as visible and infrared spectrum, radar, sonar and synthetic aperture radar signals; acoustic and magnetic signals; and optical, spectral and medical data.

Within the past two decades—particularly since 2012, following the tremendous progress in sensor development and computer techniques such as deep learning—object detection entered a rapid development period, and remarkable theoretical achievements and practical applications have emerged.

While working on modern object detection techniques, researchers are faced with various types of sensors, data, requirements and applications. This Special Issue is considered a forum to present the progress and state-of-the-art of target detection technologies and their applications. Thus, we welcome research on new algorithms for object and target detection and tracking in different types of signals and data.

- object detection
- optical remote sensing
- synthetic aperture radar object detection
- magnetic target detection and localization
- sonar object detection





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Message from the Editor-in-Chief

As the world of science becomes ever more specialized, researchers may lose themselves in the deep forest of the ever increasing number of subfields being created. This open access journal Applied Sciences has been started to link these subfields, so researchers can cut through the forest and see the surrounding, or quite distant fields and subfields to help develop his/her own research even further with the aid of this multi-dimensional network.

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